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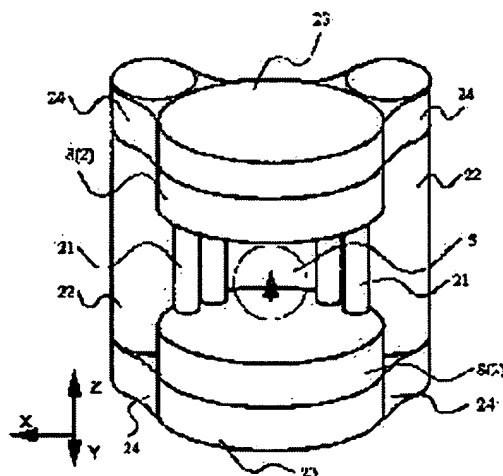
(54) SUPERCONDUCTING MAGNET DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To allow accessing to a to-be-inspected person from a magnet side and to reduce a sense of oppression over the subject to be examined by assigning a supporting means for a magnetic field generating source, so that it is on rear side with a vertical center axis passing the center of a uniform magnetic field generating region as a reference.

SOLUTION: Cooling vessels 8 which houses a superconducting coil 2, and magnetic field generating source are assigned symmetrically, while facing each other in a vertical direction with a measurement space (uniform magnetic field generation region) 5 in between.

A subject to be examined placed on an inspection table is inserted, in an Y-axis direction, in a measurement space 5 of a superconducting magnet device. With a connection tube 21 and an iron pillar 22 of the cooling vessel 8 not assigned on an X-axis, the cooling vessel 8 is supported with the



connection tube 21 at back side of a Z-axis which is the center, in vertical direction of the measurement space 5, while the iron pillar 22 and a iron plate 23 magnetically connected together at back side of the X-axis. Thus, an inspector on freely access from the side of device to the subject inserted in the measurement space 5 from outside of the device.

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